

07/13/01

	Class	Subclass
ISSUE CLASSIFICATION		

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PATENT NUMBER

U.S. **UTILITY** Patent Application

SCANNED **O.I.P.E.** *GH* **Q.A.** *Am*

PATENT DATE

APPLICATION NO. 09/903600	CONT/PRIOR F	CLASS 352 356	SUBCLASS 141	ART UNIT 2877 3	EXAMINER J. Mancuso
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APPLICANTS

Ryoichi Matsuoka

TITLE

Wafer pattern observation method and device

PTO-2040
12/99

ISSUING CLASSIFICATION												
ORIGINAL				CROSS REFERENCE(S)								
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)							
INTERNATIONAL CLASSIFICATION												

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<input type="checkbox"/> TERMINAL DISCLAIMER	DRAWINGS		CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims
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<input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S Patent. No. _____ _____ _____	_____ (Primary Examiner) (Date)		ISSUE FEE 	
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